WM2619

12-bit Parallel Input Voltage Output DAC

Production Data, June 1999, Rev 1.0

FEATURES

- **12-bit voltage output DAC**
- **Single supply 2.7V to 5.5V operation**
- **DNL ±0.4 LSB, INL ±1.5 LSB**
- **Settling time 1µs typical**
- **Low power consumption**
  - **8mW typical in slow mode - 5V supply**
  - **4.3mW typical in fast mode - 3V supply**
- **Power down mode**

APPLICATIONS

- **Battery powered test instruments**
- **Digital offset and gain adjustment**
- **Battery operated/remote industrial controls**
- **Machine and motion control devices**
- **Wireless telephone and communication systems**
- **Speech synthesis**
- **Arbitrary waveform generation**

DESCRIPTION

The WM2619 is a 12-bit voltage output, resistor string, digital-to-analogue converter. A hardware controlled power down mode is provided that reduces power consumption to 50nW. In normal operation the device dissipates 8mW at 5V or 4.3mW at 3V.

The device has been designed to interface efficiently to industry standard microprocessors and DSPs.

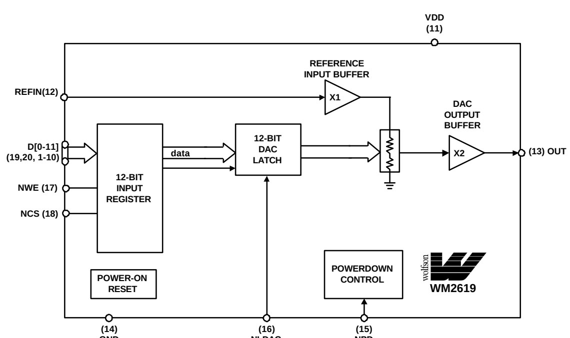
Excellent performance is delivered with a typical DNL of 0.4 LSBs and a settling time of 1µs. The output stage is buffered by a x2 gain near rail-to-rail amplifier, which features a Class A output stage. The 12 data bits are double-buffered enabling the output to be asynchronously updated under hardware control.

The device is available in a 20-pin TSSOP package. Commercial temperature (0° to 70°C) and Industrial temperature (-40° to 85°C) variants are supported.

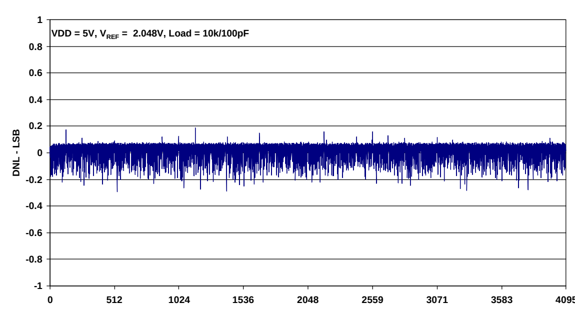
ORDERING INFORMATION

DEVICE	TEMP. RANGE	PACKAGE
WM2619CDT	0° to 70°C	20-pin TSSOP
WM2619IDT	-40° to 85°C	20-pin TSSOP

BLOCK DIAGRAM



TYPICAL PERFORMANCE



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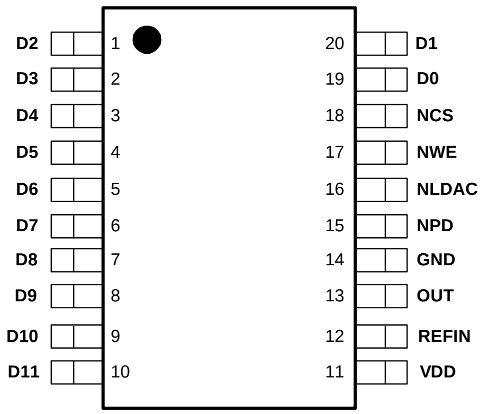
PIN CONFIGURATION



PIN DESCRIPTION

PIN NO	NAME	TYPE	DESCRIPTION
1	D2	Digital input	Digital data input.
2	D3	Digital input	Digital data input.
3	D4	Digital input	Digital data input.
4	D5	Digital input	Digital data input.
5	D6	Digital input	Digital data input.
6	D7	Digital input	Digital data input.
7	D8	Digital input	Digital data input.
8	D9	Digital input	Digital data input
9	D10	Digital input	Digital data input.
10	D11	Digital input	Digital data input (MSB).
11	VDD	Supply	Positive power supply.
12	REFIN	Analogue input	Voltage reference input.
13	OUT	Analogue output	Analogue output.
14	GND	Ground	Ground.
15	NPD	Digital input	Power down. Powers down all DACs overriding their individual power down settings and all output stages. This pin is active low.
16	NLDAC	Digital input	Load DAC. Digital input active low. NLDAC must be taken low to update the DAC latch from the holding latches.
17	NWE	Digital input	Write enable (active low).
18	NCS	Digital input	Chip select (active low).
19	D0	Digital input	Parallel data input (LSB).
20	D1	Digital input	Parallel data input.

ABSOLUTE MAXIMUM RATINGS

Absolute Maximum Ratings are stress ratings only. Permanent damage to the device may be caused by continuously operating at or beyond these limits. Device functional operating limits and guaranteed performance specifications are given under Electrical Characteristics at the test conditions specified.

ESD Sensitive Device. This device is manufactured on a CMOS process. It is therefore generically susceptible to damage from excessive static voltages. Proper ESD precautions must be taken during handling and storage of this device

CONDITION		**MIN**	**MAX**
Digital Supply voltage, VDD to GND			7V
Reference input voltage		-0.3V	VDD + 0.3V
Digital input voltages		-0.3V	VDD + 0.3V
Operating temperature range, T_A	WM2619C	0°C	70°C
	WM2619I	-40°C	85°C
Storage temperature		-65°C	150°C
Lead temperature 1.6mm (1/16 inch) soldering for 10 seconds			260°C

RECOMMENDED OPERATING CONDITIONS

PARAMETER	**SYMBOL**	**TEST CONDITIONS**	**MIN**	**TYP**	**MAX**	**UNIT**
Supply voltage	VDD		2.7		5.5	V
High-level digital input voltage	V_{IH}	VDD = 2.7V to 5.5V	2			V
Low-level digital input voltage	V_{IL}	VDD = 2.7V to 5.5V			0.8	V
Reference voltage to REFIN	V_{REF}	See Note			VDD - 1.5	V
Load resistance	R_L		2	10		kΩ
Load capacitance	C_L				100	pF
Operating free-air temperature	T_A	WM2619C	0		70	°C
		WM2619I	-40		85	°C

Note: Reference input voltages greater than VDD/2 will cause output saturation for large DAC codes.

ELECTRICAL CHARACTERISTICS

Test Conditions:
R_L = 10kΩ, C_L = 100pF. VDD = 5V ± 10%, V_{REF} = 2.048V and VDD = 3V ± 10%, V_{REF} = 1.024V over recommended operating free-air temperature range (unless noted otherwise)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Static DAC Specifications						
Resolution			12			bits
Integral non-linearity	INL	See Note 1		±1.5	±4	LSB
Differential non-linearity	DNL	See Note 2		±0.4	±1	LSB
Zero code error	ZCE	See Note 3		3	±20	mV
Gain error	GE	See Note 4		0.25	±0.5	% FSR
D.c. power supply rejection ratio	d.c. PSRR	See Note 5		0.5		mV/V
Zero code error temperature coefficient		See Note 6		3		ppm/°C
Gain error temperature coefficient		See Note 6		1		ppm/°C
DAC Output Specifications						
Output voltage range			0		VDD - 0.4	V
Output load regulation		2kΩ to 10kΩ load See Note 7		0.1	0.3	%
Power Supplies						
Active supply current	I_{DD}	No load, V_{IH} = VDD, V_{IL} = 0V VDD = 5V, V_{REF} = 2.048V VDD = 3V, V_{REF} = 1.024V See Note 8		 1.6 1.4	 3.0 2.7	 mA mA
Power down supply current		No load, all digital inputs 0V or VDD See Note 9		0.01	10	µA
Dynamic DAC Specifications						
Slew rate		DAC code 128 to 4095, 10%-90% See Note 10		8		V/µs
Settling time		DAC code 128 to 4095 See Note 11		1		µs
Glitch energy		Code 2047 to 2048		5		nV-s
Signal to noise ratio	SNR	fs = 480ksps, f_{OUT} = 1kHz, BW = 20kHz, TA = 25°C See Note 12	65	78		dB
Signal to noise and distortion ratio	SNRD	fs = 480ksps, f_{OUT} = 1kHz, BW = 20kHz, TA = 25°C See Note 12	58	67		dB
Total harmonic distortion	THD	fs = 480ksps, f_{OUT} = 1kHz, BW = 20kHz, TA=25°C See Note 12		-68	-60	dB
Spurious free dynamic range	SPFDR	fs = 480ksps, f_{OUT} = 1kHz, BW = 20kHz, TA = 25°C See Note 12	60	72		dB
Reference						
Reference input resistance	R_{REFIN}			10		MΩ
Reference input capacitance	C_{REFIN}			5		pF
Reference feedthrough		V_{REF} = 1V_{PP} at 1kHz + 1.024Vdc, DAC code 0		-60		dB
Reference input bandwidth		V_{REF} = 0.2V_{PP} + 1.024V d.c. DAC code 2048		1.4		MHz

Test Conditions:

R_L = 10kΩ, C_L = 100pF. VDD = 5V ± 10%, V_{REF} = 2.048V and VDD = 3V ± 10%, V_{REF} = 1.024V over recommended operating free-air temperature range (unless noted otherwise)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Digital Inputs						
High level input current	I_{IH}	Input voltage = VDD			1	μA
Low level input current	I_{IL}	Input voltage = 0V			-1	μA
Input capacitance	C_I			8		pF

Notes:

1. **Integral non-linearity** (INL) is the maximum deviation of the output from the line between zero and full scale (excluding the effects of zero code and full scale errors).
2. **Differential non-linearity** (DNL) is the difference between the measured and ideal 1LSB amplitude change of any adjacent two codes. A guarantee of monotonicity means the output voltage changes in the same direction (or remains constant) as a change in digital input code.
3. **Zero code error** is the voltage output when the DAC input code is zero.
4. **Gain error** is the deviation from the ideal full scale output excluding the effects of zero code error.
5. **Power supply rejection ratio** is measured by varying V_{DD} from 4.5V to 5.5V and measuring the proportion of this signal imposed on the zero code error and the gain error.
6. **Zero code error** and **Gain error** temperature coefficients are normalised to full scale voltage.
7. **Output load regulation** is the difference between the output voltage at full scale with a 10kΩ load and 2kΩ load. It is expressed as a percentage of the full scale output voltage with a 10kΩ load.
8. $\mathbf{I_{DD}}$ is measured while continuously writing code 2048 to the DAC. For $V_{IH} < V_{DD}$ - 0.7V and V_{IL} > 0.7V supply current will increase.
9. **Typical supply current** in power down mode is 10nA. Production test limits are wider for speed of test.
10. **Slew rate** results are for the lower value of the rising and falling edge slew rates.
11. **Settling time** is the time taken for the signal to settle to within 0.5LSB of the final measured value for both rising and falling edges. Limits are ensured by design and characterisation, but are not production tested.
12. **SNR, SNRD, THD** and **SPFDR** are measured on a synthesised sinewave at frequency f_{OUT} generated with a sampling frequency fs.

SERIAL INTERFACE

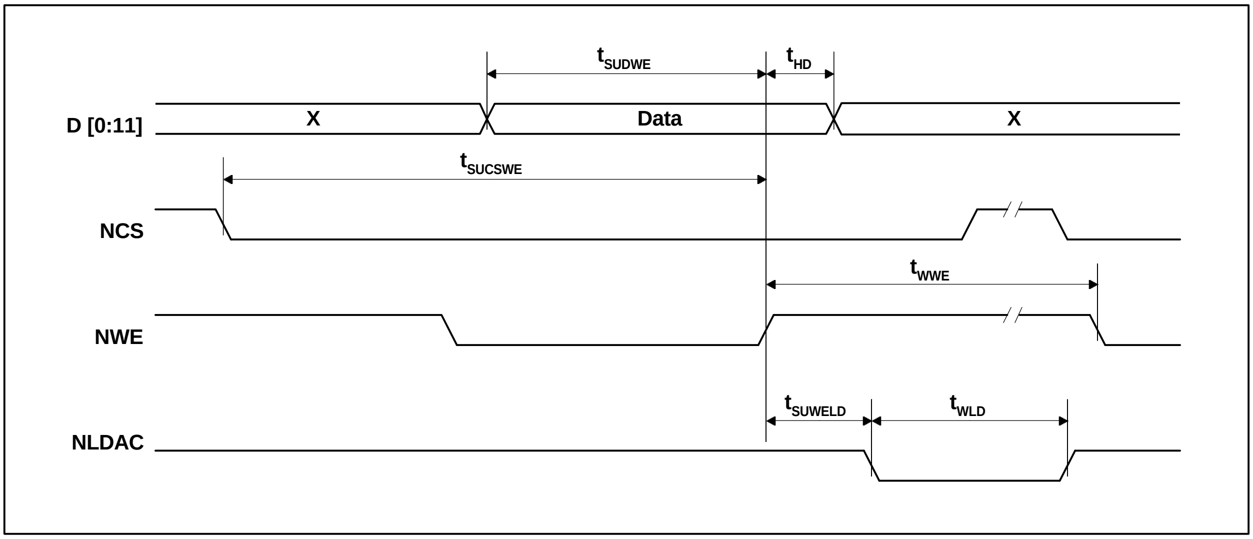


Figure 1 Timing Diagram

Test Conditions:
R_L = 10kΩ, C_L = 100pF. VDD = 5V ± 10%, V_{REF} = 2.048V and VDD = 3V ± 10%, V_{REF} = 1.024V over recommended operating free-air temperature range (unless noted otherwise)

SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t_{SUCSWE}	Setup time NCS low before positive NWE edge	13			ns
t_{SUDWE}	Setup time data ready before positive NWE edge	9			ns
T_{HD}	Data hold after positive NWE edge	0			ns
t_{SUWELD}	Setup time NWE high before NLDAC low	0			ns
t_{WWE}	High pulse width of NWE	10			ns
t_{WLD}	Low pulse width of NLDAC	10			ns

TYPICAL PERFORMANCE GRAPHS

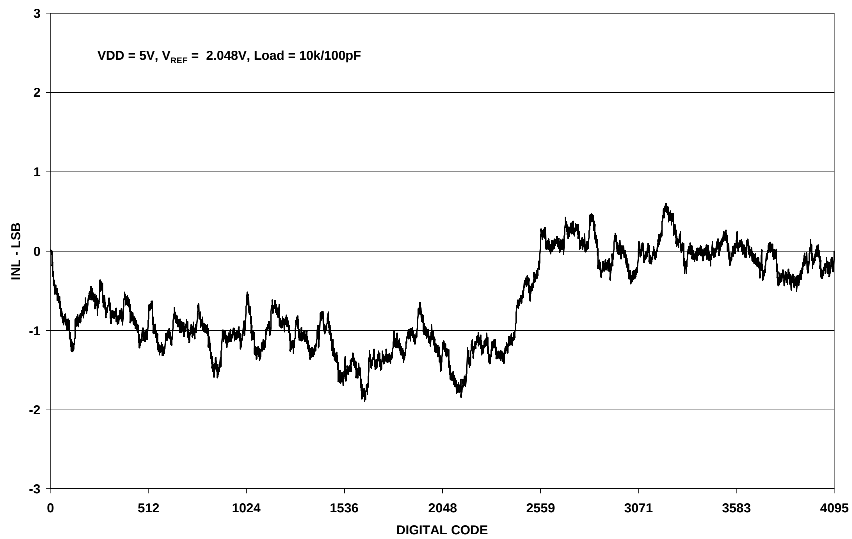


Figure 2 Integral Non-Linearity

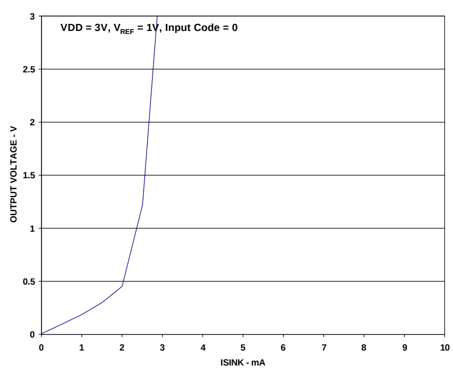


Figure 3 Sink Current VDD = 3V

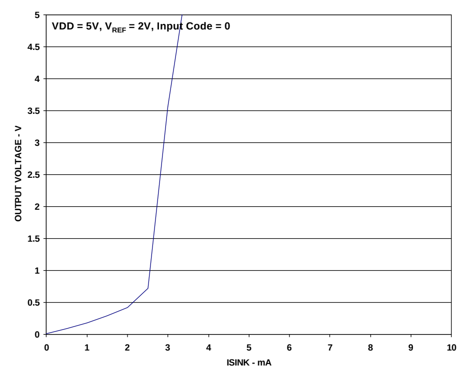


Figure 4 Sink Current VDD = 5V

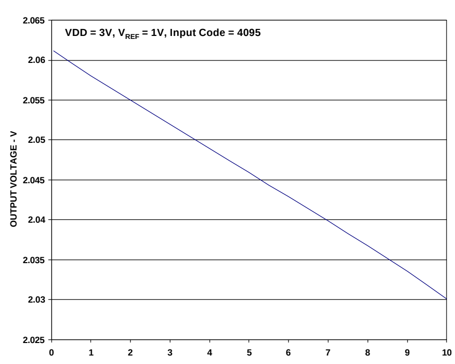


Figure 5 Source Current VDD = 3V

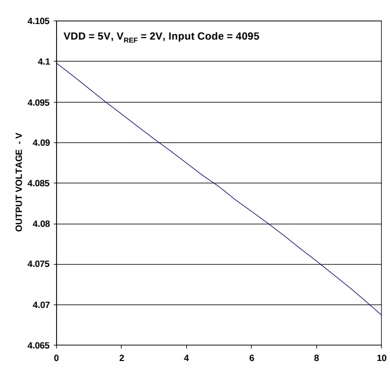


Figure 6 Source Current VDD = 5V

DEVICE DESCRIPTION

GENERAL FUNCTION

The device uses a resistor string network buffered with an op amp to convert 12-bit digital data to analogue voltage levels (see Block Diagram). The output voltage is determined by the reference input voltage and the input code according to the following relationship:

$$\text{Output voltage} = 2(V_{REF})\frac{CODE}{4096}$$

INPUT			OUTPUT
1111	1111	1111	$2(V_{REF})\frac{4095}{4096}$
	:		:
1000	0000	0001	$2(V_{REF})\frac{2049}{4096}$
1000	0000	0000	$2(V_{REF})\frac{2048}{4096} = V_{REF}$
0111	1111	1111	$2(V_{REF})\frac{2047}{4096}$
	:		:
0000	0000	0001	$2(V_{REF})\frac{1}{4096}$
0000	0000	0000	0V

Table 1 Binary Code Table (0V to 2V_{REFIN} Output), Gain = 2

POWER ON RESET

An internal power-on-reset circuit resets the DAC register to all 0s on power-up.

BUFFER AMPLIFIER

The output buffer has a near rail-to-rail output with short circuit protection and can reliably drive a 2kΩ load with a 100pF load capacitance.

EXTERNAL REFERENCE

The reference voltage input is buffered which makes the DAC input resistance independent of code. The REFIN pin has an input resistance of 10MΩ and an input capacitance of typically 5pF. The reference voltage determines the DAC full-scale output.

HARDWARE CONFIGURATION OPTIONS

The WM2619 has two configuration options that are controlled by device pins.

DEVICE POWERDOWN

The device can be powered-down by pulling pin NPD (pin 15) high. This powers down the DAC. This will reduce power consumption significantly. When the power down function is released the device reverts to the DAC code set prior to power down.

DAC UPDATE

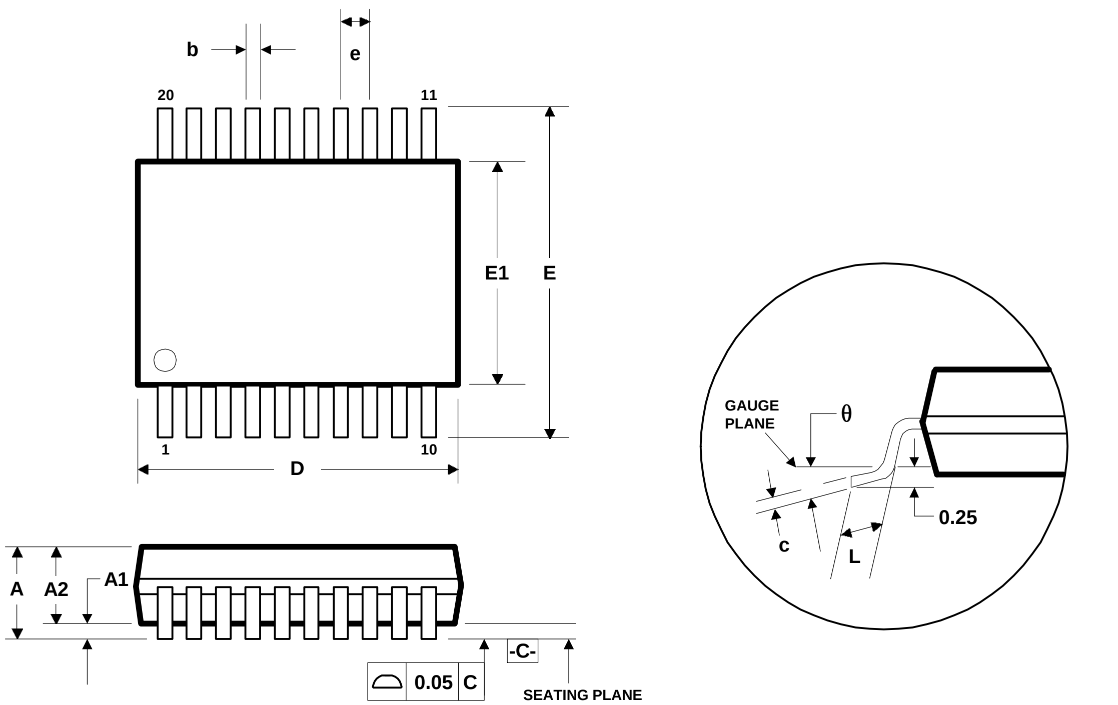
The NLDAC pin (Pin 16) can be held high to prevent serial word writes from updating the DAC latch. By writing the new value to the DAC then pulling NLDAC low, the new DAC code is loaded into the DAC latch.

PARALLEL INTERFACE

The device registers data on the positive edge of NWE (Pin 17). It must be enabled with NCS (Pin 18) low.

PACKAGE DIMENSIONS

DT: 20 PIN TSSOP (6.5 x 4.4 x 1.0 mm) **DM008.C**



Symbols	Dimensions (mm)		
	MIN	NOM	MAX
A	-----	-----	1.20
A_1	0.05	-----	0.15
A_2	0.80	1.00	1.05
b	0.19	-----	0.30
c	0.09	-----	0.20
D	6.40	6.50	6.60
e	0.65 BSC		
E	6.4 BSC		
E_1	4.30	4.40	4.50
L	0.45	0.60	0.75
θ	0^o	-----	8^o
REF:	JEDEC.95, MO-153		

NOTES:
A. ALL LINEAR DIMENSIONS ARE IN MILLIMETERS.
B. THIS DRAWING IS SUBJECT TO CHANGE WITHOUT NOTICE.
C. BODY DIMENSIONS DO NOT INCLUDE MOLD FLASH OR PROTRUSION, NOT TO EXCEED 0.25MM.
D. MEETS JEDEC.95 MO-153, VARIATION = AC. REFER TO THIS SPECIFICATION FOR FURTHER DETAILS.